

Search Notes

Application/Control No.

10/760,618

Examiner

Michael J. Hayes

Applicant(s)/Patent under
Reexamination

FURTH ET AL.

Art Unit

3767

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(604/68-72,522 435/285.1,285.3,455,459 600/104 606/119) updated search - see search history	3/11/2006	MJH